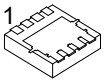
50A, 30V N-CHANNEL ENHANCEMENT MODE POWER MOSFET TRANSISTOR



PDFN3×3

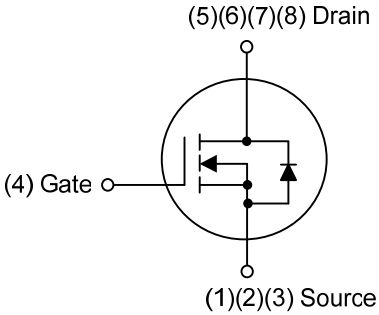
■ DESCRIPTION

The UTC **UT50N03V** is an N-channel enhancement power MOSFET using UTC's advanced technology in the various components of gate charge and capacitance have been optimized to reduce switching losses. Low gate resistance and very low Miller charge enable excellent performance with both adaptive and fixed dead time gate drive circuits. Very low RDS(ON) has been maintained to provide a sub logic-level device, designed to minimize losses in power conversion applications.

■ FEATURES

* $R_{DS(ON)}$ ≤ 4.5 mΩ @ V_{GS}=10V, I_D=20A
  $R_{DS(ON)}$ ≤ 5.3 mΩ @ V_{GS}=4.5V, I_D=15A
  $R_{DS(ON)}$ ≤ 8 mΩ @ V_{GS}=2.5V, I_D=12A
* High Switching Speed
* High Current Capacity

■ SYMBOL



■ ORDERING INFORMATION

Ordering Number		Package	Pin Assignment								Packing
Lead Free	Halogen Free		1	2	3	4	5	6	7	8	
UT50N03VL-P3030-R	UT50N03VG-P3030-R	PDFN3×3	S	S	S	G	D	D	D	D	Tape Reel

Note: Pin Assignment: S: Source G: Gate D: Drain

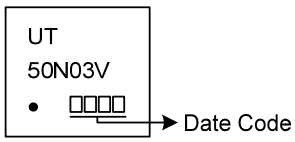
UT50N03VG-P3030-R

(1)Packing Type — (1) R: Tape Reel

(2)Package Type — (2) P3030: PDFN3×3

(3)Green Package — (3) G: Halogen Free and Lead Free, L: Lead Free

■ MARKING



■ ABSOLUTE MAXIMUM RATINGS (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	30	V
Gate-Source Voltage		V_{GSS}	±12	V
Drain Current	Continuous	I_D	50	A
	Pulsed	I_{DM}	100	A
Avalanche Energy (Note 3)	Single Pulsed	E_{AS}	51	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	1.5	V/ns
Power Dissipation		P_D	34	W
Junction Temperature		T_J	150	°C
Storage Temperature		T_{STG}	-55 ~ 150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.
2. Repetitive Rating: Pulse width limited by maximum junction temperature.
3. L=0.1mH, I_{AS}=32A, V_{DD}=20V, R_G=25Ω, Starting T_J = 25°C
4. I_{SD} ≤ 30A, di/dt ≤ 200A/μs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	75	°C/W
Junction to Case	θ_{JC}	3.67	°C/W

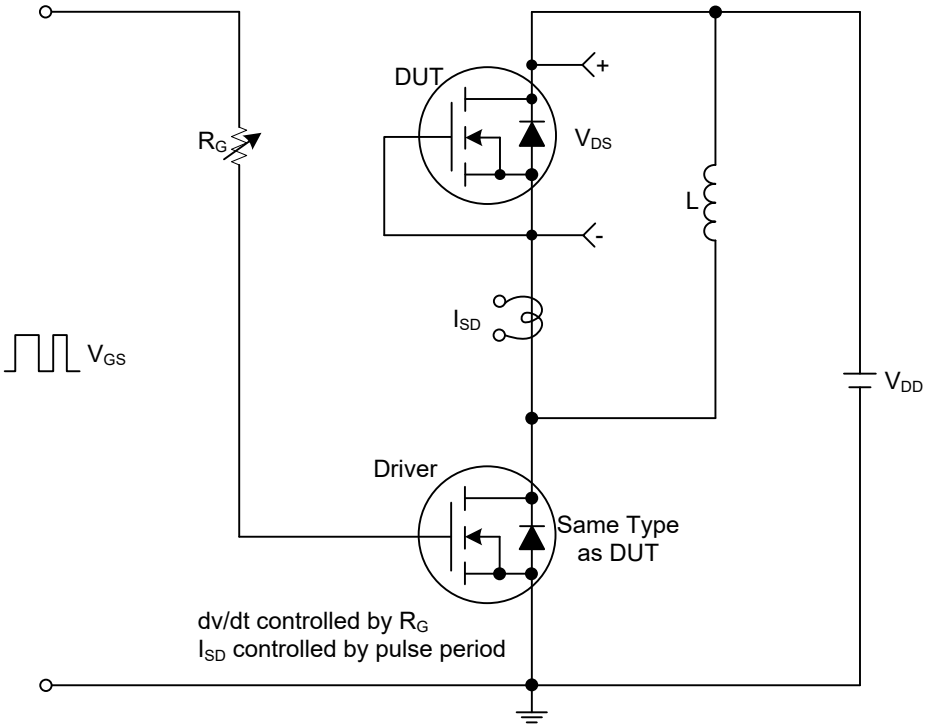
Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

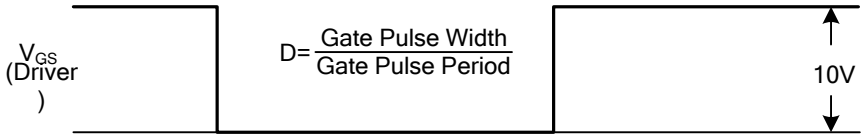
■ ELECTRICAL CHARACTERISTICS (T_J=25°C, unless otherwise specified)

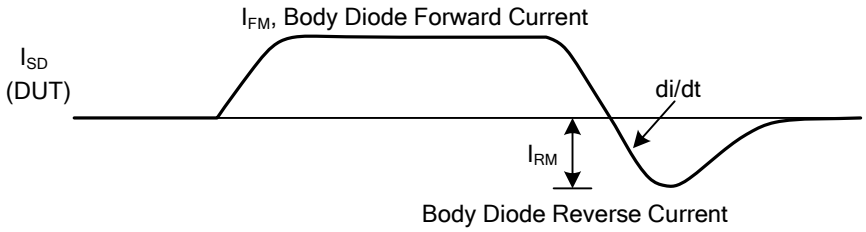
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	I_D=250μA, V_{GS}=0V	30			V
Drain-Source Leakage Current		I_{DSS}	V_{DS}=30V, V_{GS}=0V			1	μA
Gate- Source Leakage Current	Forward	I_{GSS}	V_{GS}=+12V, V_{DS}=0V			+100	nA
	Reverse		V_{GS}=-12V, V_{DS}=0V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	V_{DS}=V_{GS}, I_D=250μA	0.5		1.5	V
Static Drain-Source On-State Resistance		$R_{DS(ON)}$	V_{GS}=10V, I_D=20A			4.5	mΩ
			V_{GS}=4.5V, I_D=15A			5.3	mΩ
			V_{GS}=2.5V, I_D=12A			8.0	mΩ
DYNAMIC PARAMETERS							
Input Capacitance		C_{ISS}	V_{GS}=0V, V_{DS}=25V, f=1.0MHz		3330		pF
Output Capacitance		C_{OSS}			330		pF
Reverse Transfer Capacitance		C_{RSS}			300		pF
SWITCHING PARAMETERS							
Total Gate Charge		Q_G	V_{DS}=24V, V_{GS}=4.5V, I_D=50A (Note1, 2)		65		nC
Gate to Source Charge		Q_{GS}			8.5		nC
Gate to Drain Charge		Q_{GD}			24		nC
Turn-ON Delay Time		$t_{D(ON)}$	V_{DS}=15V, V_{GS}=10V, I_D=50A, R_G=3.3Ω (Note1, 2)		9		ns
Rise Time		t_R			20		ns
Turn-OFF Delay Time		$t_{D(OFF)}$			80		ns
Fall-Time		t_F			28		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS							
Maximum Body-Diode Continuous Current		I_S				50	A
Maximum Body-Diode Pulsed Current		I_{SM}				100	A
Drain-Source Diode Forward Voltage		V_{SD}	I_S=50A, V_{GS}=0V			1.5	V
Reverse Recovery Time (Note 1)		t_{rr}	I_S=30A, V_{GS}=0V, dI/dt=100A/μs		90		ns
Reverse Recovery Charge		Q_{rr}			80		nC

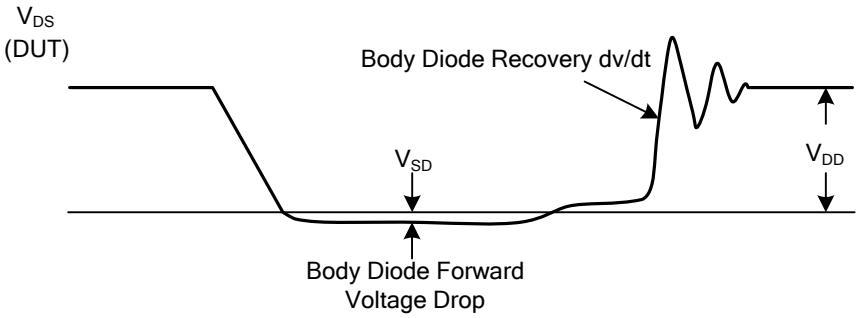
Notes: 1. Pulse Test: Pulse width ≤ 300μs, Duty cycle ≤ 2%.
2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS



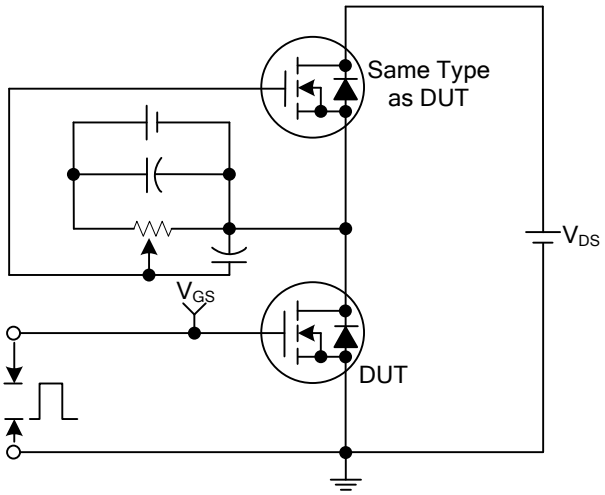




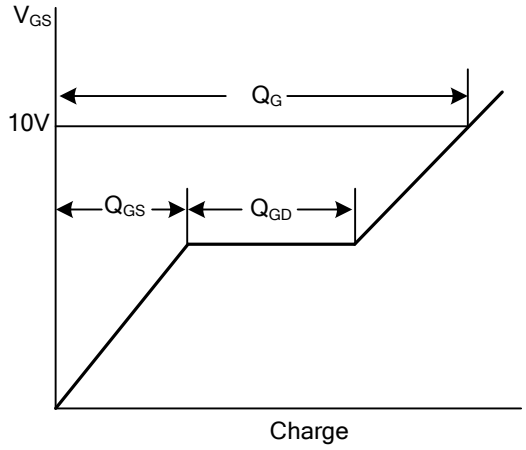


Peak Diode Recovery dv/dt Test Circuit and Waveforms

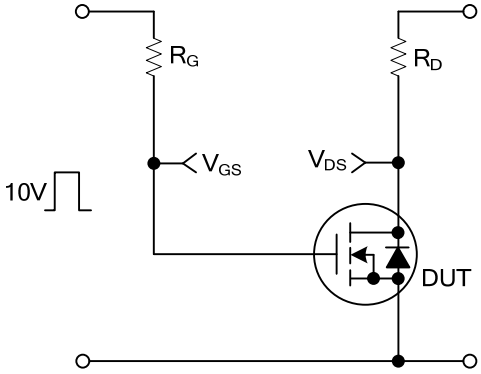
■ TEST CIRCUITS AND WAVEFORMS



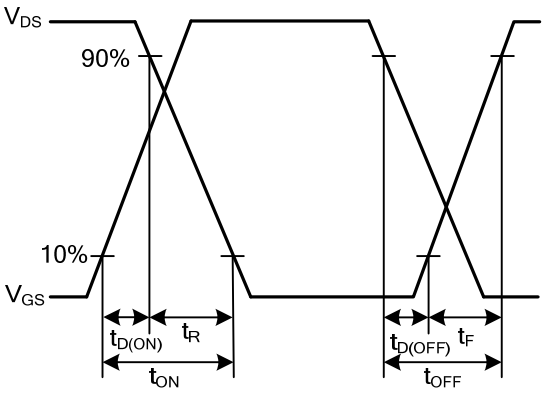
Gate Charge Test Circuit



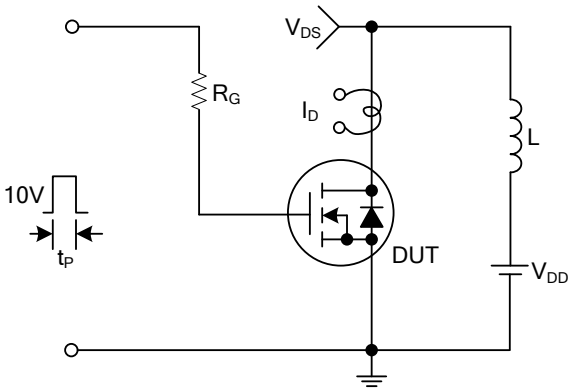
Gate Charge Waveforms



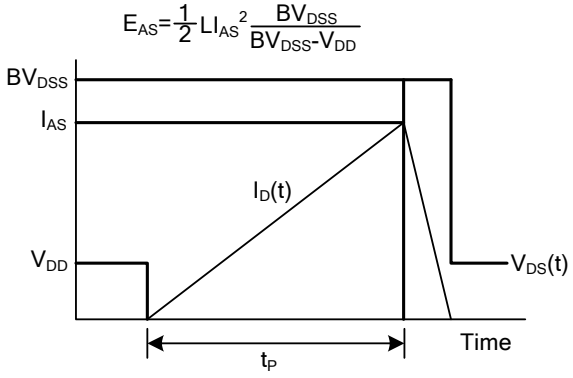
Resistive Switching Test Circuit



Resistive Switching Waveforms



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms